

American National Standard

*American National Standard
Recommended Practice for
Laser Safety Measurements
for Hazard Evaluation*



**Laser Institute
of America**
Laser Applications and Safety



ANSI®
Z136.4 – 2010
Revision of
ANSI Z136.4-2005

**American National Standard
Recommended Practice for
Laser Safety Measurements
for Hazard Evaluation**

**Secretariat
Laser Institute of America**

**Approved April 22, 2010
American National Standards Institute, Inc.**

**American
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Published by

**Laser Institute of America
13501 Ingenuity Drive, Suite 128
Orlando, FL 32826**

ISBN: #0-912035-78-1

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